

SEMICONDUCTOR TEST SYSTEM WITH TIME CRITICAL SEQUENCE  
GENERATION USING GENERAL PURPOSE OPERATING SYSTEM

Abstract of the Disclosure

5 A semiconductor test system is capable of time critical  
sequence generation using a general purpose operating system.  
The semiconductor test system includes a tester hardware for  
providing power sources and test patterns to a device under  
test, a host computer operated by a general purpose operating  
system, a configuration software for computing configuration  
10 data and timing data based on a test program, a device driver  
for providing a power trigger and a signal trigger to the  
tester hardware, and a hardware timer for producing an  
interrupt signal. The device driver causes to start the test  
pattern and to deactivate the power sources upon receiving  
15 the interrupt signal.

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